

Final Project Report

Wide-Band Transimpedance Amplifier

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Navin: Test Bed Simulations, Circuit Design, Circuit Simulation for Every Stage, Report

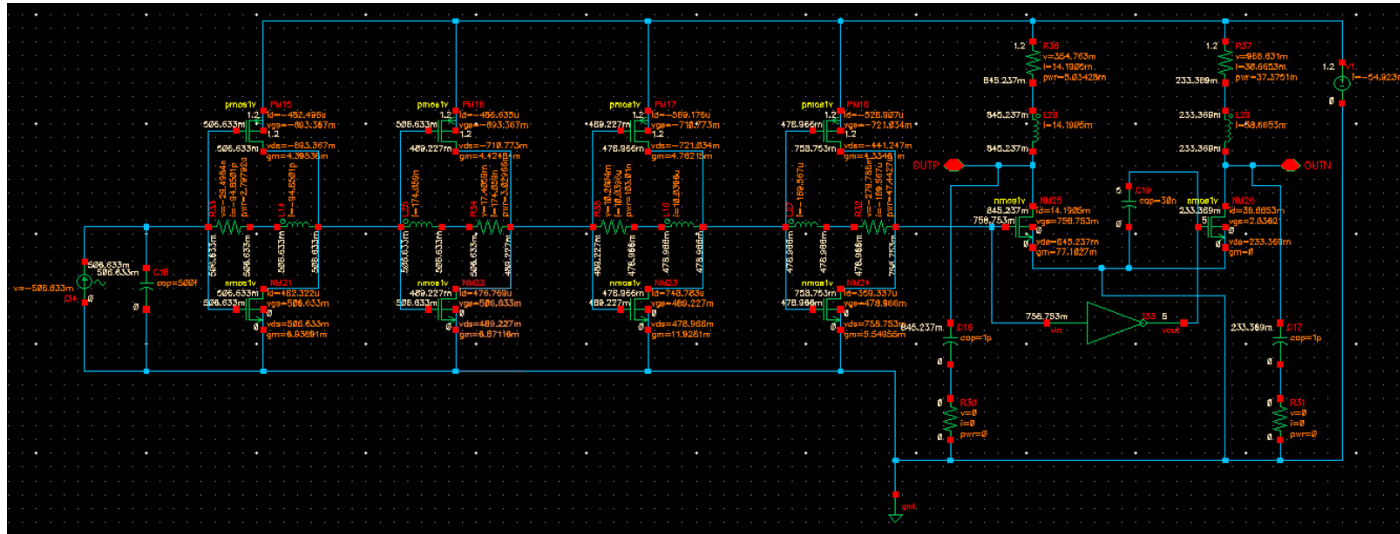
Parnika: Test Bed Analysis, Differential Stage Simulation, Noise Simulation and Analysis, Report

Ziqiong: Literature Review and Research, Power, Gain, Bandwidth, Swing Theoretical Calculations, Report

All of us: Gain, Bandwidth and Differential Swing Analysis

8th December 2024

Circuit Schematic and Performance Summary



Schematic

Performance	Target	Simulated	Calculated	Error (%)
Power	<50mW	65mW	117.4mW	- 80%
Gain	>74dB	77dB at 5GHz (<1dB variation)	~ 70dB	+ 10%
Bandwidth	> 5GHz	5.011 GHz	~ 5.4 GHz	- 6%
Differential Swing	>100mV	404mV (for 10uA input)	800mV (max)	-
Input Referred Noise	<50pA/sqrt(Hz)	3.72 e-11 V/sqrt(Hz) (at 5GHz)	1.28 e-8 V/sqrt(Hz)	-

Performance Summary

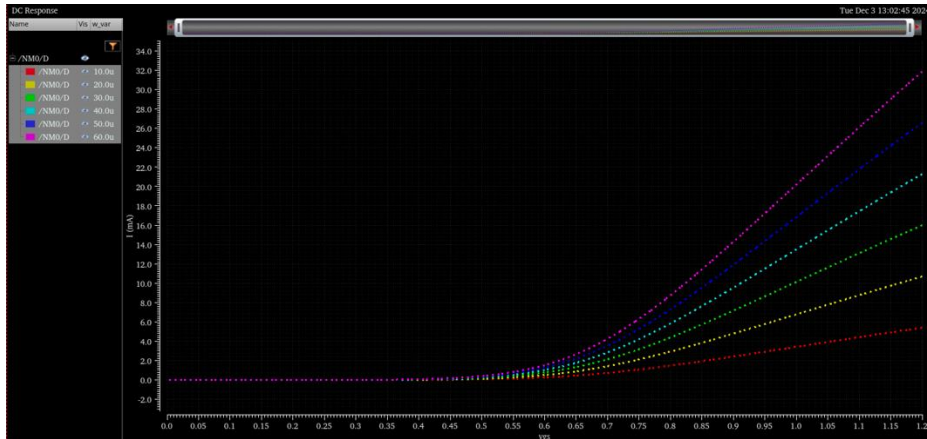
How the Architecture is Decided?

Setting up a testbed in Cadence and plot the gm-Vgs, and Id-Vgs curves for various transistor width from 10um to 60um with a step size of 10um.

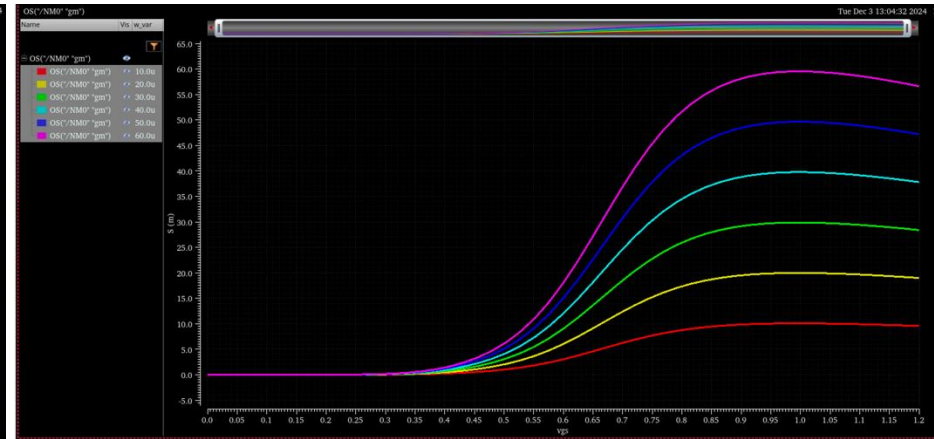
- Observation: As width increases gm also increase as seen in the formula.
- Analysis : We can increase the width to increase the gain.

$$g_m = \left. \frac{\partial I_D}{\partial V_{GS}} \right|_{V_{DS, \text{const.}}} \\ = \mu_n C_{ox} \frac{W}{L} (V_{GS} - V_{TH})$$

$$g_m = \sqrt{2\mu_n C_{ox} \frac{W}{L} I_D}$$



Id-Vgs



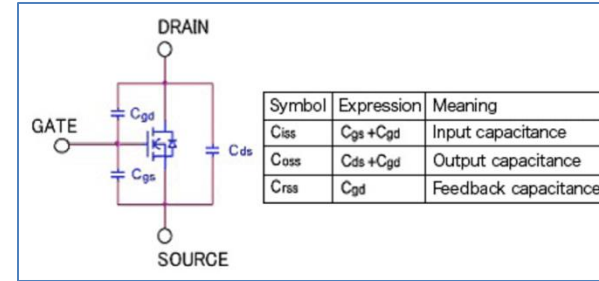
gm-Vgs

How the Architecture is Decided?

Conducting a DC analysis in Cadence and extract the values of Cgs, Cgd, Cds, Cdb, and Csb for a current density of 0.3mA/um. Considering the absolute value.

- Observation: The parasitic capacitance generally increases as the width of the transistor increases. Cgs and Cgd are more dominant)

1. OP("/W/NM0" "cgs"): -6.55146×10^{-15} F
2. OP("/W/NM0" "cds"): 1.20794×10^{-18} F
3. OP("/W/NM0" "cgd"): -1.46636×10^{-15} F
4. OP("/W/NM0" "cdb"): -233.123×10^{-21} F
5. OP("/W/NM0" "csb"): -394.876×10^{-18} F



- Analysis: In general, we observed that the width for the NMOS is set to a workable minimum like 200 nm, that depends on the process. As PMOS transistors are intrinsically weaker they need wider width compared to the NMOS. Usually, 2x wider is a good start so 400 nm for example, but we changed it according to the need for bandwidth and gain.

Outputs					
	Name/Signal/Expr	Value	Plot	Save	Save Options
1	OP("/NM0" "cgs")	-6.55146f	<input checked="" type="checkbox"/>	<input type="checkbox"/>	
2	OP("/NM0" "cds")	1.20794a	<input checked="" type="checkbox"/>	<input type="checkbox"/>	
3	OP("/NM0" "cgd")	-1.46636f	<input checked="" type="checkbox"/>	<input type="checkbox"/>	
4	OP("/NM0" "cdb")	-233.123z	<input checked="" type="checkbox"/>	<input type="checkbox"/>	
5	OP("/NM0" "csb")	-394.876a	<input checked="" type="checkbox"/>	<input type="checkbox"/>	

Parasitic Capacitances

How the Architecture is Decided?

Setting up a testbed for f_T calculation of a transistor with the width of 10 μ m under various levels of current densities: 0.3mA/ μ m, 0.5mA/ μ m, 1mA/ μ m. Comparing it against our analytical results based on the parasitic extraction from last section and explaining if the results match or not.

- Definition: The frequency at which the current gain becomes unity. f_T is typically used as an indicator to evaluate the high-frequency capability. Smaller parasitic capacitances C_{gs} and C_{gd} are desirable for higher unity-gain frequency
- Observation: Increasing V_{gs} (for increasing current density), decreases the f_T .
- Analysis: Therefore, if we require more f_T , we should take lower V_{gs} .

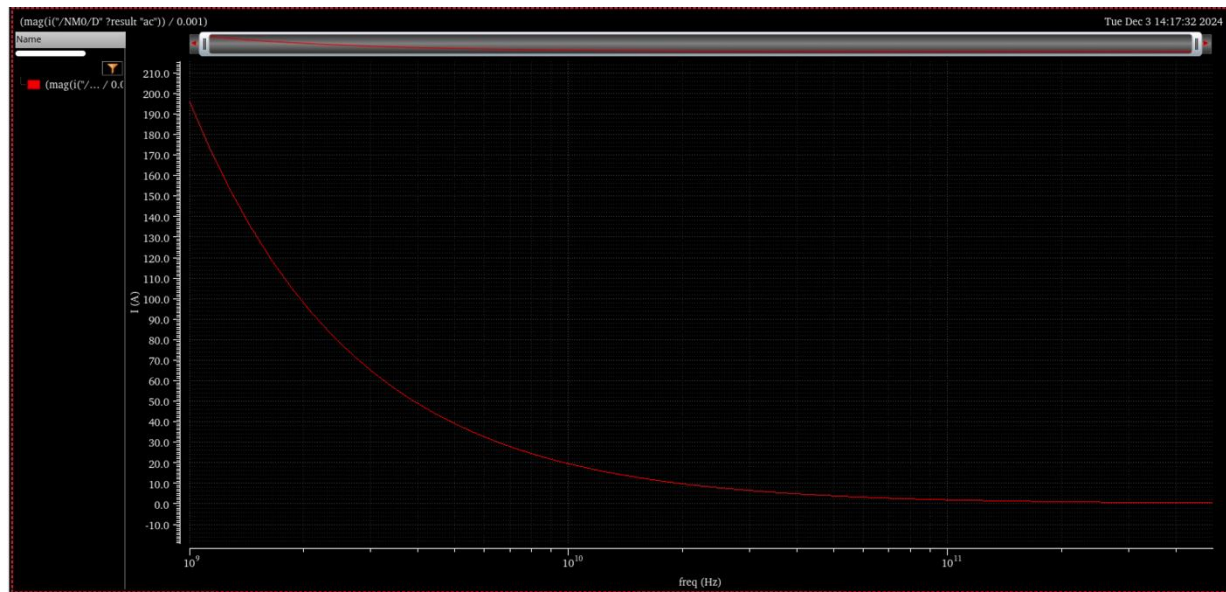
$$f_T = \frac{g_m}{2\pi(C_{gs} + C_{gd})}$$

$$g_m = \frac{2I_D}{V_{GS} - V_{TH}}$$

$$f_T \propto \frac{g_m}{C_{gs}} = \frac{2I_D/(V_{GS} - V_{TH})}{C_{gs}} \quad \text{and} \quad J = \frac{I_D}{W \times L}$$

How the Architecture is Decided?

Setting up a testbed for F_t calculation of a transistor with the width of 10 μm under various levels of current densities: 0.3mA/ μm , 0.5mA/ μm , 1mA/ μm . Comparing it against our analytical results based on the parasitic extraction from last section and explaining if the results match or not.



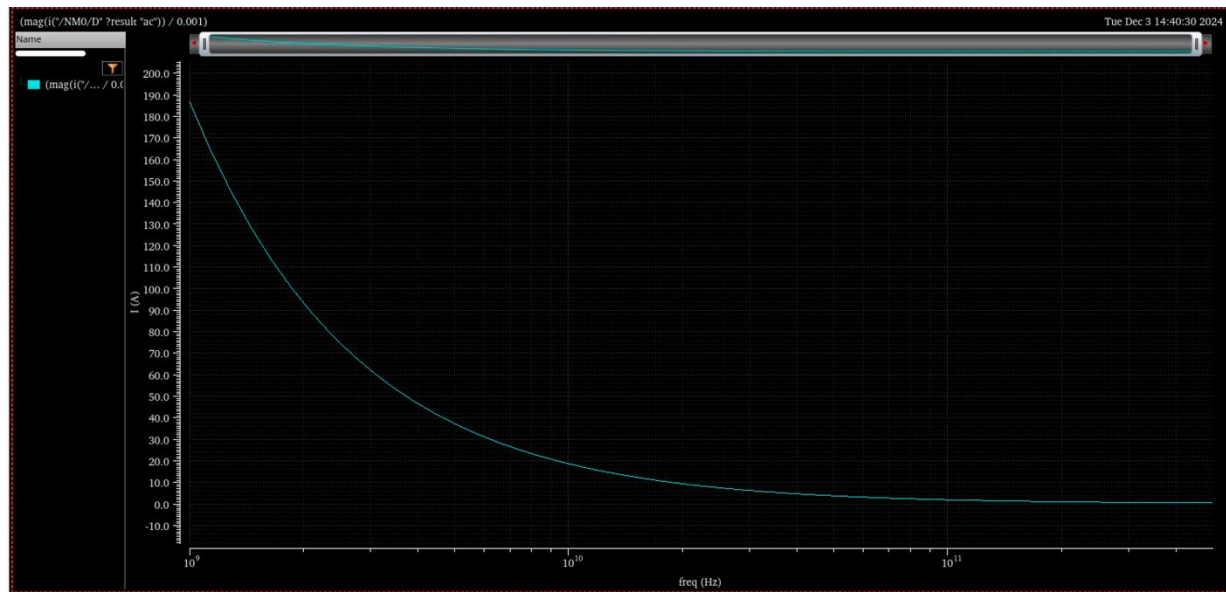
Design Variables		
	Name	Value
1	vgs	958m
2	w_var	10u

Outputs				
	Name/Signal/Expr	Value	Plot	Save
1	ids		<input type="checkbox"/>	<input checked="" type="checkbox"/>
2	$(\text{mag}(I('NM0/D' ?result "ac")) / 0.001)$	wave	<input checked="" type="checkbox"/>	<input type="checkbox"/>
3	$\text{unityGainFreq}((\text{mag}(I('NM0/D' ?result "ac")) / 0.001))$	199.627G	<input checked="" type="checkbox"/>	<input type="checkbox"/>

$J=0.3\text{mA}/\mu\text{m}$, $V_{gs}=958\text{mV}$

How the Architecture is Decided?

Setting up a testbed for I_t calculation of a transistor with the width of 10 μ m under various levels of current densities: 0.3mA/ μ m, 0.5mA/ μ m, 1mA/ μ m. Comparing it against our analytical results based on the parasitic extraction from last section and explaining if the results match or not.



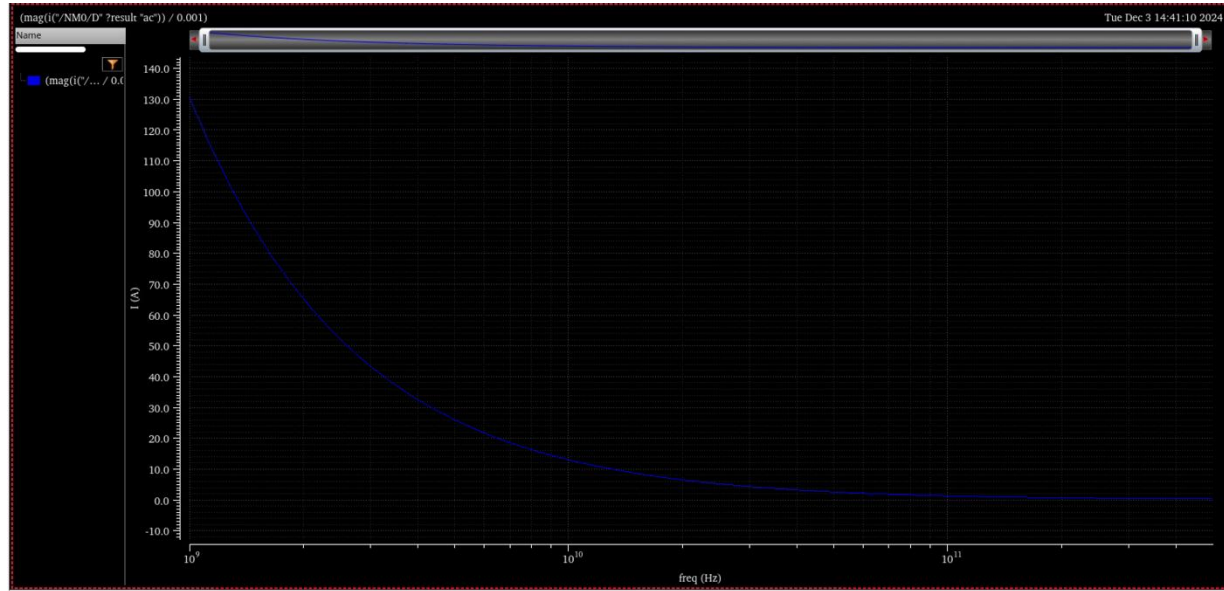
Design Variables	
Name	Value
1 vgs	1.15
2 w_var	10u

Outputs				
Name/Signal/Expr	Value	Plot	Save	Save Options
1 ids		<input type="checkbox"/>	<input checked="" type="checkbox"/>	yes
2 (mag(i('NM0/D' ?result "ac")) / 0.001)	wave	<input checked="" type="checkbox"/>	<input type="checkbox"/>	
3 unityGainFreq((mag(i('NM0/D' ?result "ac")) / 0.001))	190.103G	<input checked="" type="checkbox"/>	<input type="checkbox"/>	

$J=0.5\text{mA}/\mu\text{m}$, $V_{gs}=1.15\text{V}$

How the Architecture is Decided?

Setting up a testbed for F_t calculation of a transistor with the width of $10\mu\text{m}$ under various levels of current densities: $0.3\text{mA}/\mu\text{m}$, $0.5\text{mA}/\mu\text{m}$, $1\text{mA}/\mu\text{m}$. Comparing it against our analytical results based on the parasitic extraction from last section and explaining if the results match or not.

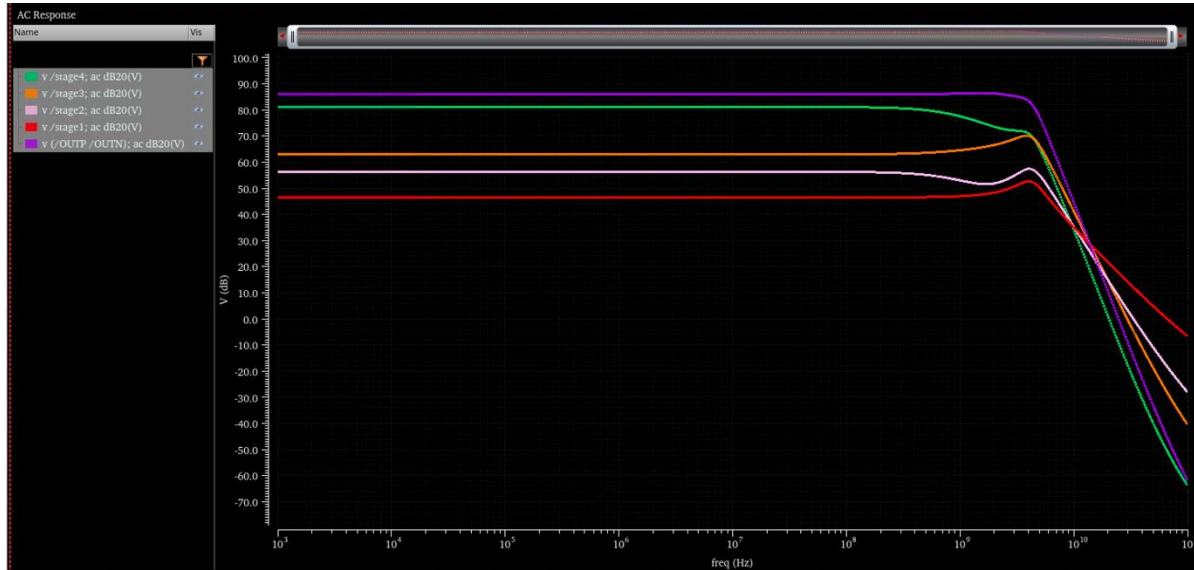


Design Variables		
	Name	Value
1	vgs	1.75
2	w_var	10u

Outputs					
	Name/Signal/Expr	Value	Plot	Save	Save Options
1	ids		<input type="checkbox"/>	<input checked="" type="checkbox"/>	yes
2	$(mag(iC/NM0/D^2 \text{ result 'ac')}) / 0.001$	wave	<input checked="" type="checkbox"/>	<input type="checkbox"/>	
3	$unityGainFreq((mag(iC/NM0/D^2 \text{ result 'ac')}) / 0.001)$	132.951G	<input checked="" type="checkbox"/>	<input type="checkbox"/>	

$J=1\text{mA}/\mu\text{m}$, $V_{gs}=1.75\text{V}$

Performance Evaluation: Gain



Gain Contributions of Each Stage

Stage	Simulated (dB)	Calculated (dB)	Error (%)
1	43.372	48	- 8.91
2	10.895	13	- 16
3	7.822	11	- 28.8
4	18.111	11	+ 64
5	5.911	9	- 34

Performance Evaluation Table

Stages: 5

Techniques:

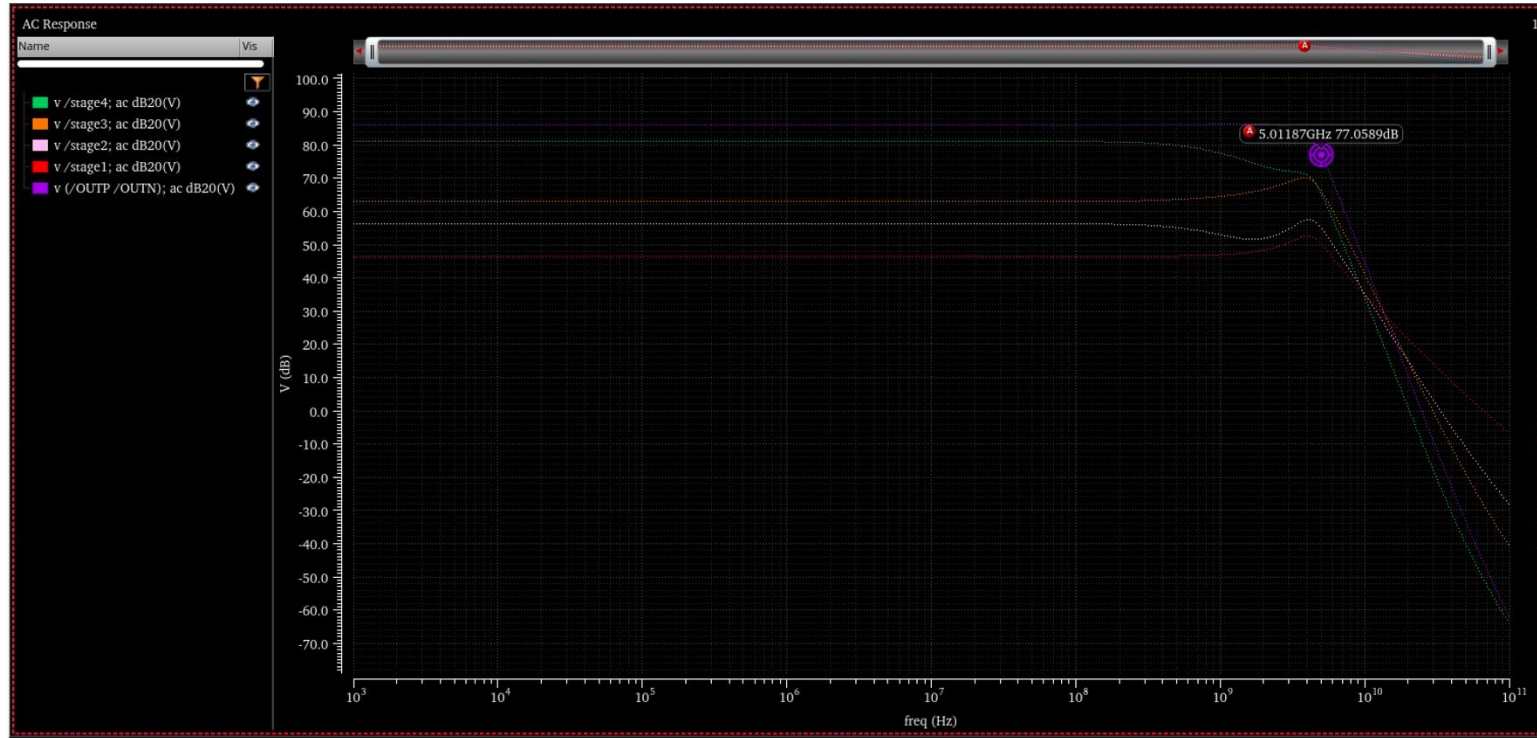
- Feedback (provided gain)
- Differential TIAs (made the bandwidth flat at high frequency)
- Capacitor at negative differential W/L maintained by increasing fingers (increased gain)

Explored Techniques:

- Inductive ladder (reduced bandwidth)
- Common source and common gate for differential (did not increase gain much)

Simulation:
AC and DC

Performance Evaluation: Bandwidth

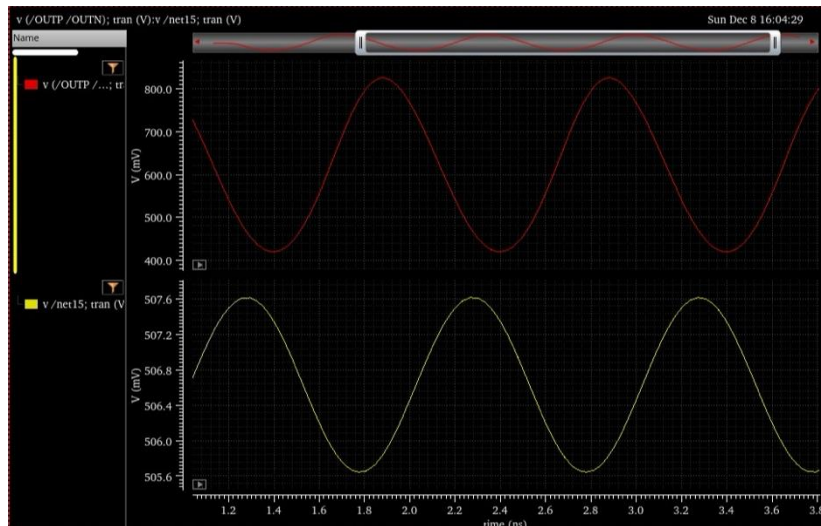


Simulation:
AC and XF

Result:
Bandwidth:
5.01 GHz

Final Gain and Bandwidth

Performance Evaluation: Differential Swing



Differential Swing

Swing	Simulated (mV)	Simulated Amplitude (mV)	Gain
Max Output	824.76	824.76 - 420.66 = 404.1	= 404.1/1.97 = 205.12
Min Output	420.66		
Max Input	507.61	507.61 - 505.64 = 1.97	
Min Input	505.64		

Differential Swing Performance Evaluation Table

Simulation: Transient Analysis

Output: Sine Wave

Amplitude: 404mV , Frequency: 1GHz

Input Signal: Sine Wave

Amplitude: 10uA, Frequency: 1GHz

Comment:

1. Phase Delay: Due use of multiple stages

2. Calculation: $V_{out,max} = V_{DD} - V_{DS,sat}$

$V_{out,min} = V_{DS,sat}$

$V_{out,max} = 1.2V - 0.2V = 1V$

$V_{out,min} = 0.2V$

Voltage Swing = $V_{out,max} - V_{out,min}$

= $1V - 0.2V = 0.8V$

(Max swing can be achieved at ~22uA input)

Performance Evaluation: Noise

Simulation: Transient Analysis

Input amplitude: 1u A to 20u A

Frequency: 1 GHz

Output Coupled Capacitor: 1p F

Resistance: 50 Ohms.

$$\frac{\overline{V_n^{2out}(total)}}{A_v^2} = \overline{V_n^{2in}}$$

$$\overline{V_{n,out}^2} = \frac{kT}{C_{PD}'}$$

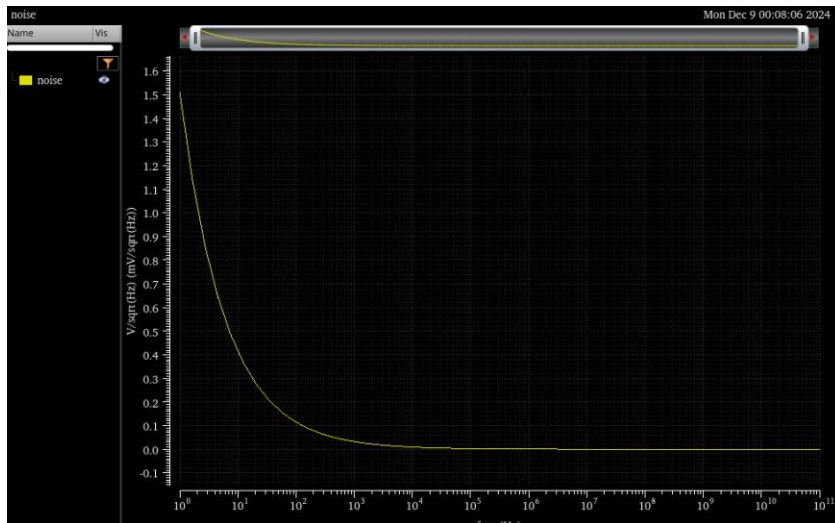
Noise	Simulated	Calculated
Referred	1.39 e-21	1.65 e-16

Noise

Noise Performance Evaluation Table

Device	Param	Noise Contribution	% Of Total
/PM15/xrg/r1	thermal_noise	5.74477e-14	63.54
/NM21	id	1.5219e-14	16.83
/PM15	id	9.25493e-15	10.24
Spot Noise Summary (in V^2/Hz) at 5G Hz Sorted By Noise Contributors			
Total Summarized Noise = 9.04083e-14			
Total Input Referred Noise = 1.39093e-21			

Total Input Referred Noise



References

- [1] Huang, Yipeng, and Jun Yin. "Design of a three-stage high-bandwidth CMOS transimpedance amplifier." *Columbia University, no date*: 1-5. (For TIA)
- [2] Wu, Chia-Hsin, et al. "CMOS wideband amplifiers using multiple inductive-series peaking technique." *IEEE journal of solid-state Circuits* 40.2 (2005): 548-552.
- [3] Network Theory Broadband Circuit Design, Fall 2024, Texas A&M University
- [4] Analui, Behnam, and Ali Hajimiri. "Bandwidth enhancement for transimpedance amplifiers." *IEEE Journal of Solid-State Circuits* 39.8 (2004): 1263-1270. (For Differential)